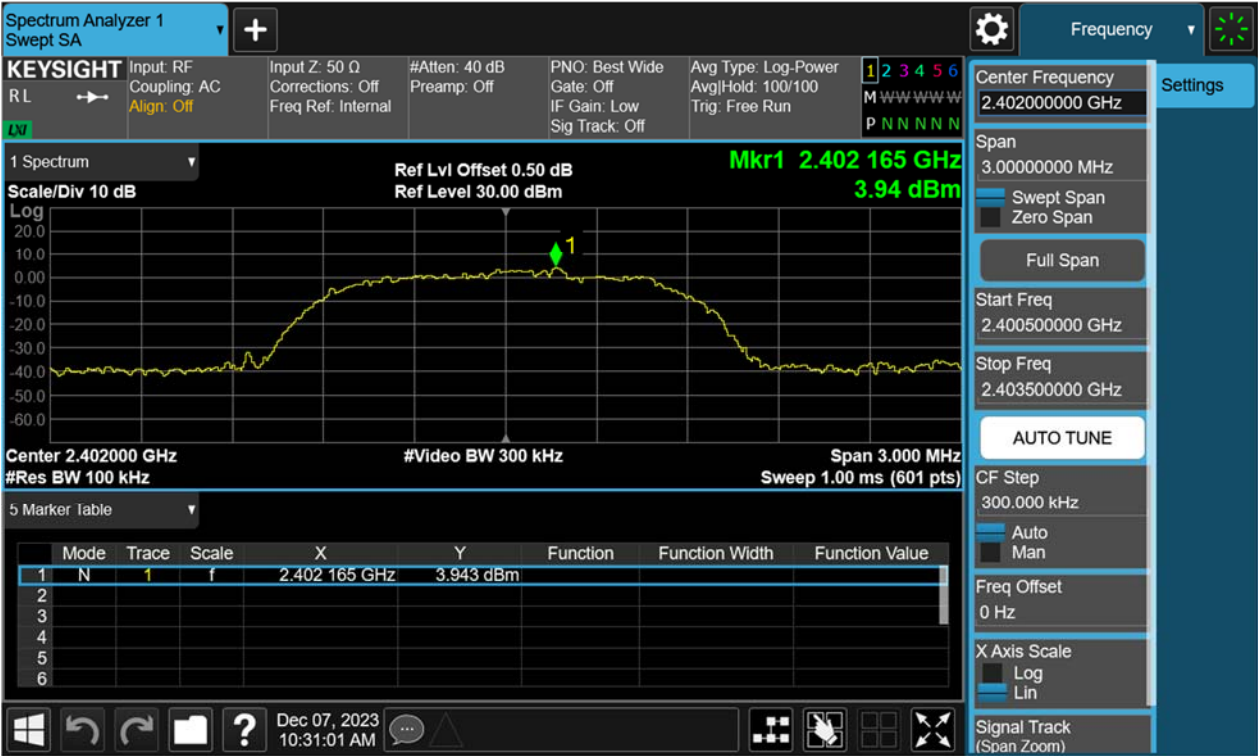


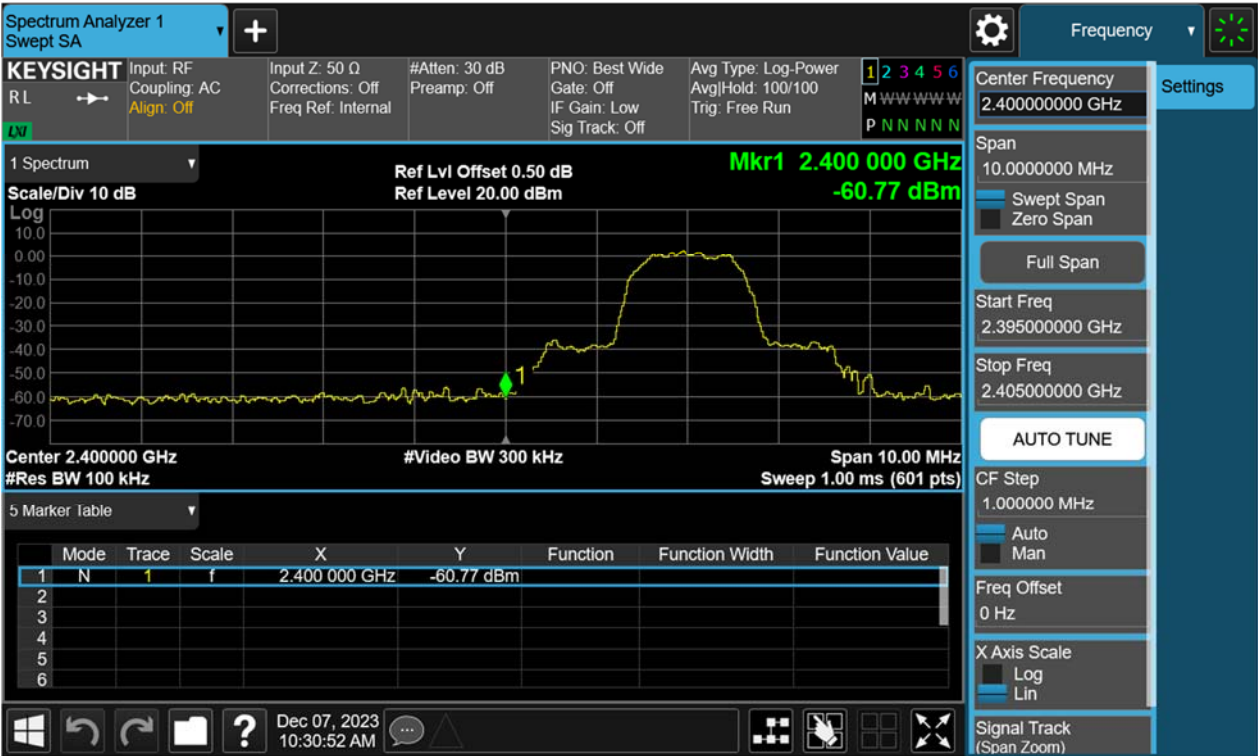
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Figure 25: Conducted Spurious Emission & Authorized-band band-edge, 2402MHz, 8-DPSK Carrier Level



Band Edge



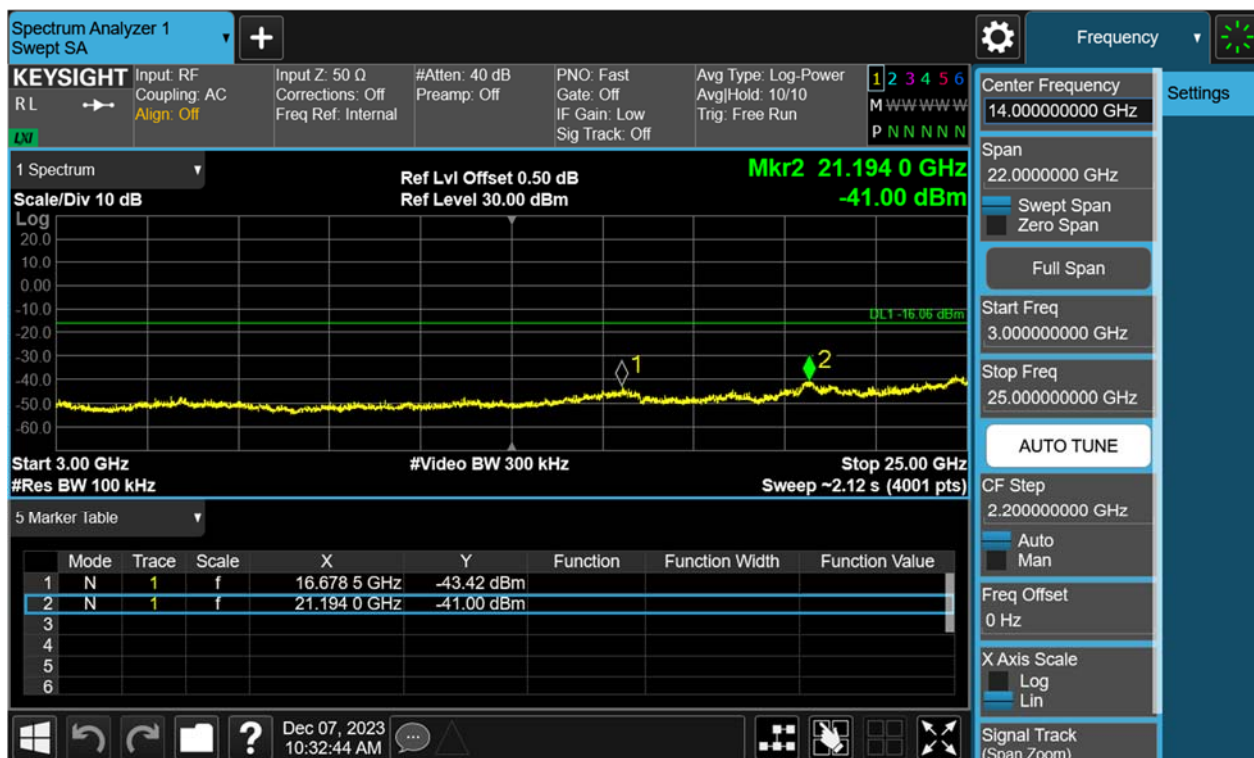
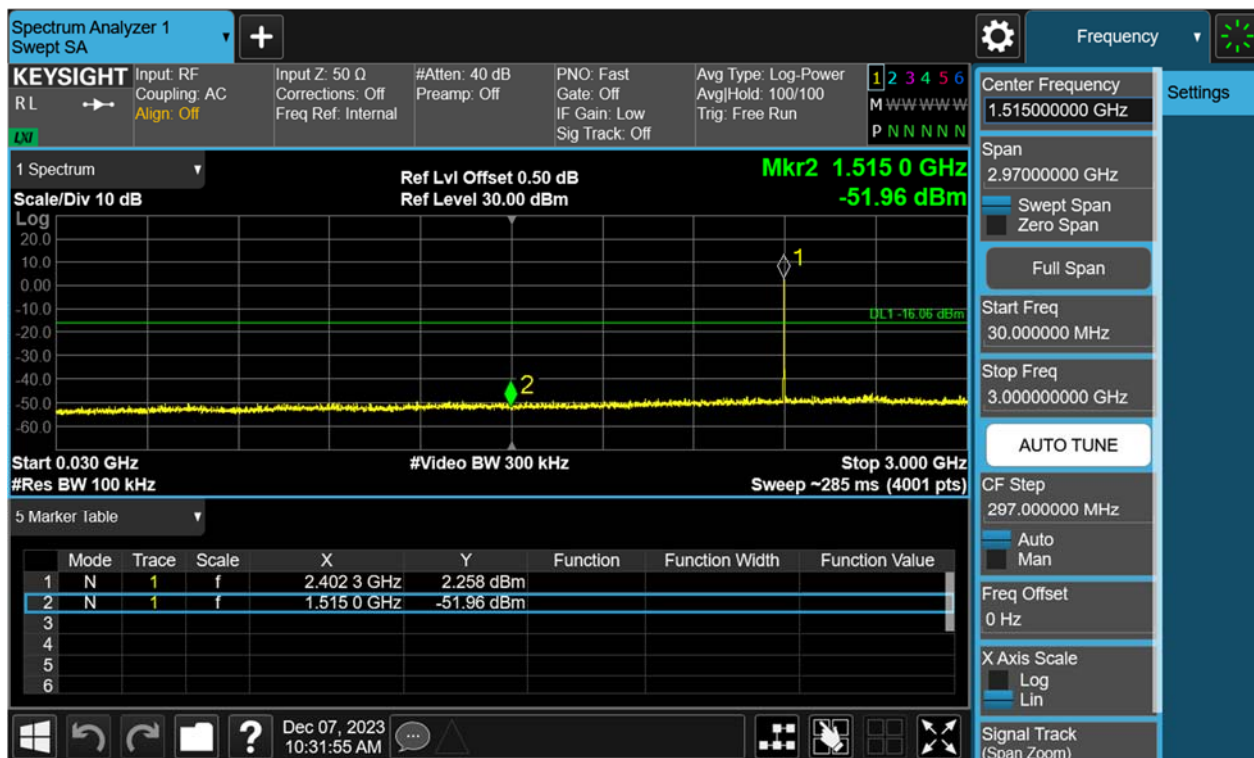
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Conducted spurious emissions 30MHz-25GHz



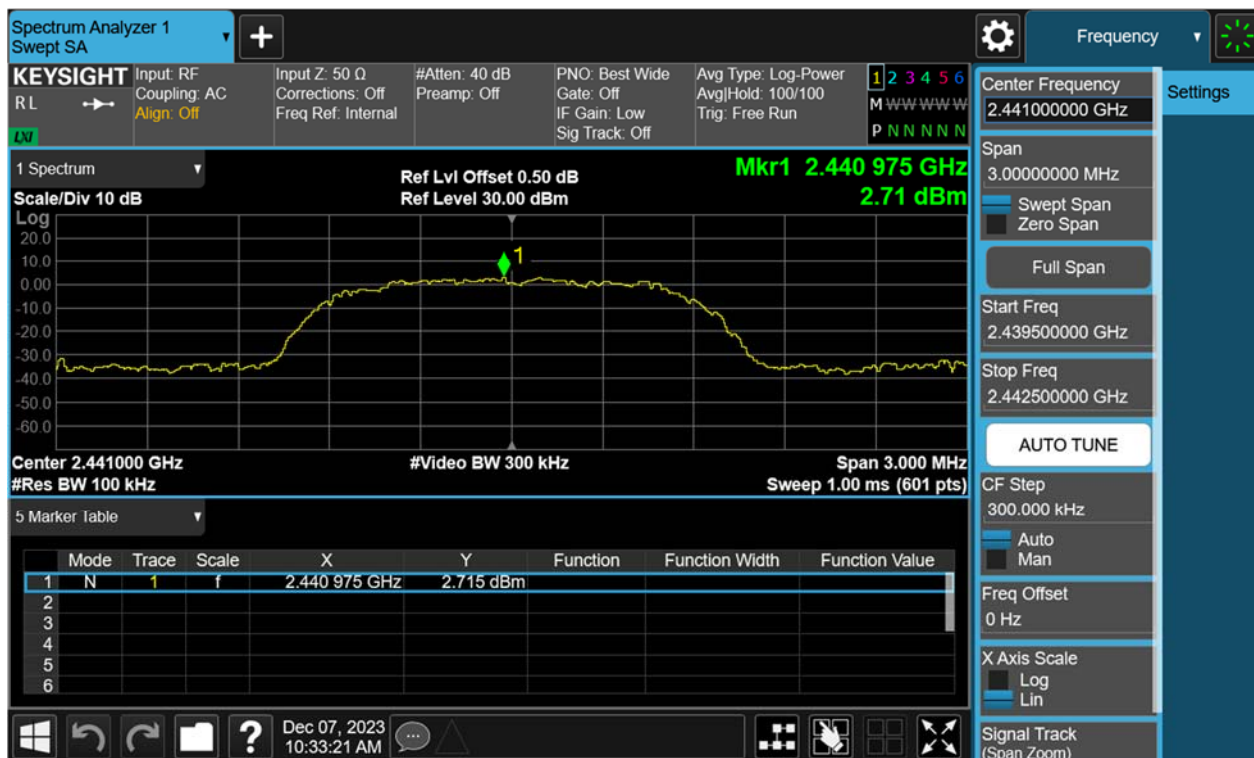
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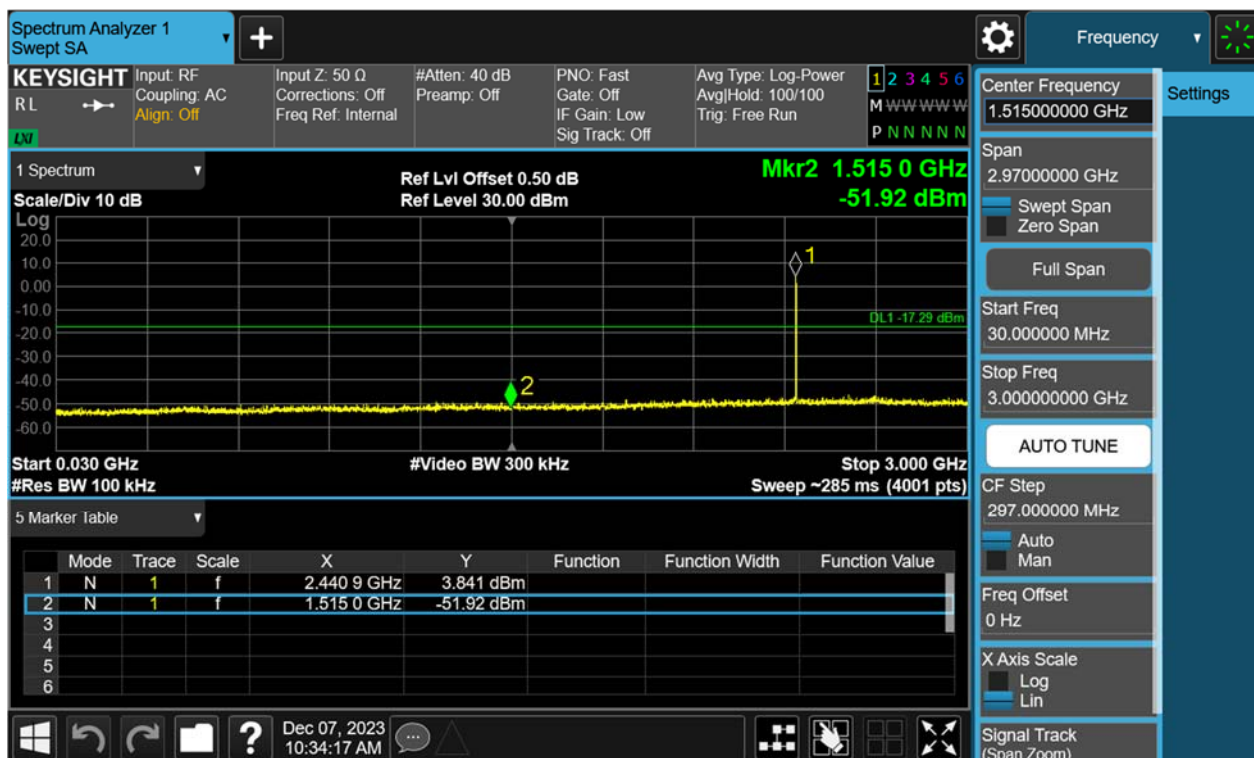
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Figure 26: Conducted Spurious Emission & Authorized-band band-edge, 2441MHz, 8-DPSK Carrier Level



Conducted spurious emissions 30MHz-25GHz



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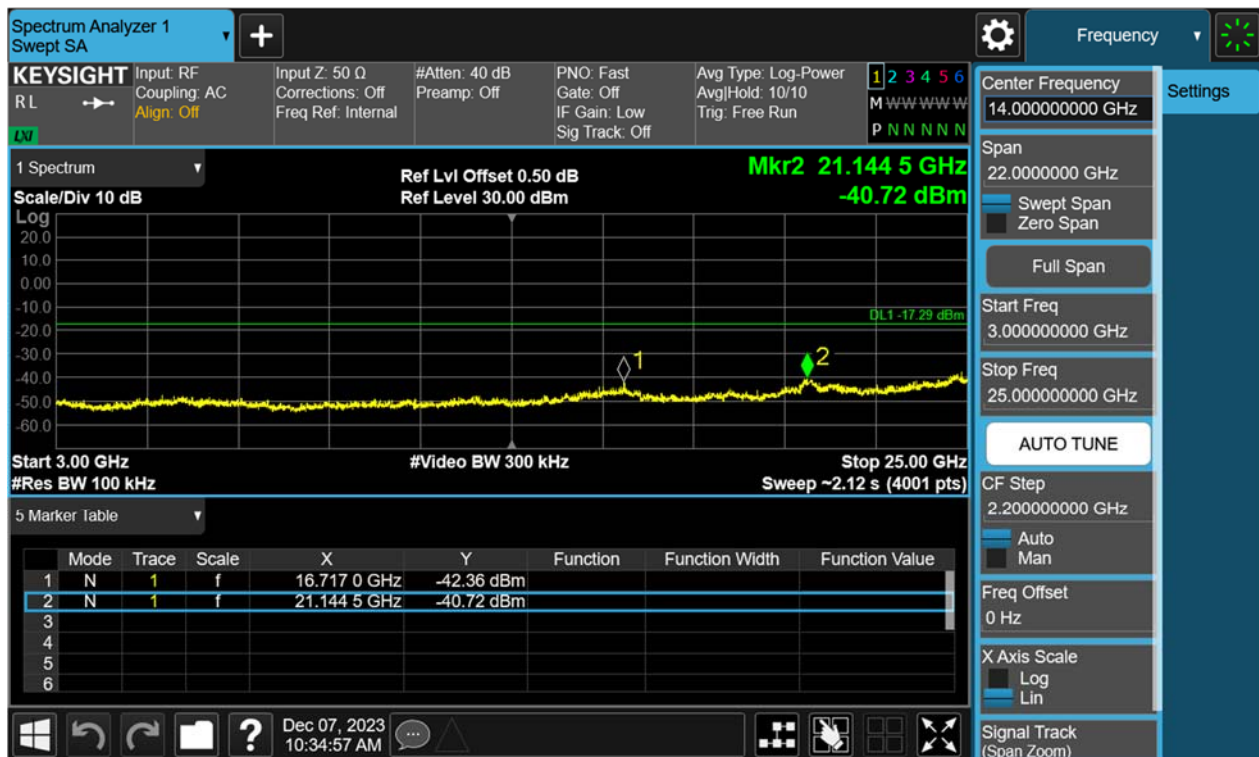


Figure 27: Conducted Spurious Emission & Authorized-band band-edge, 2480MHz, 8-DPSK Carrier Level



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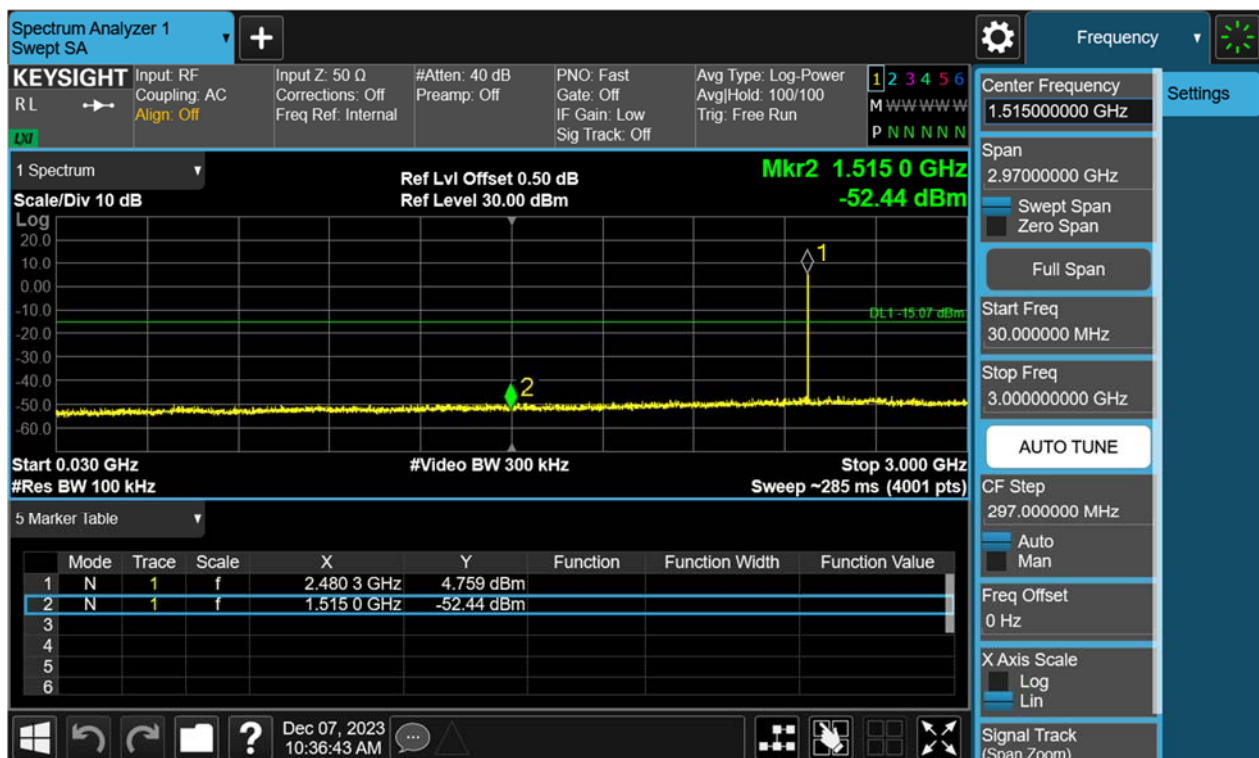
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Band Edge



Conducted spurious emissions 30MHz-25GHz



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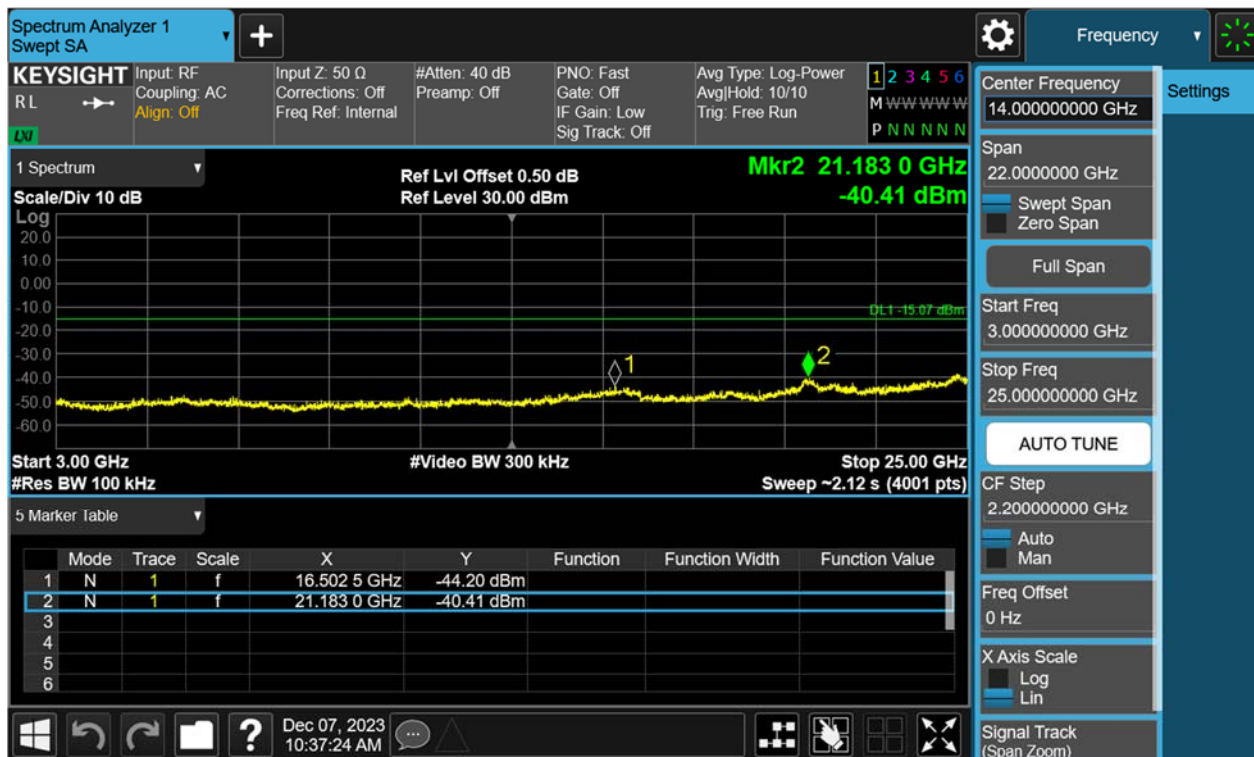
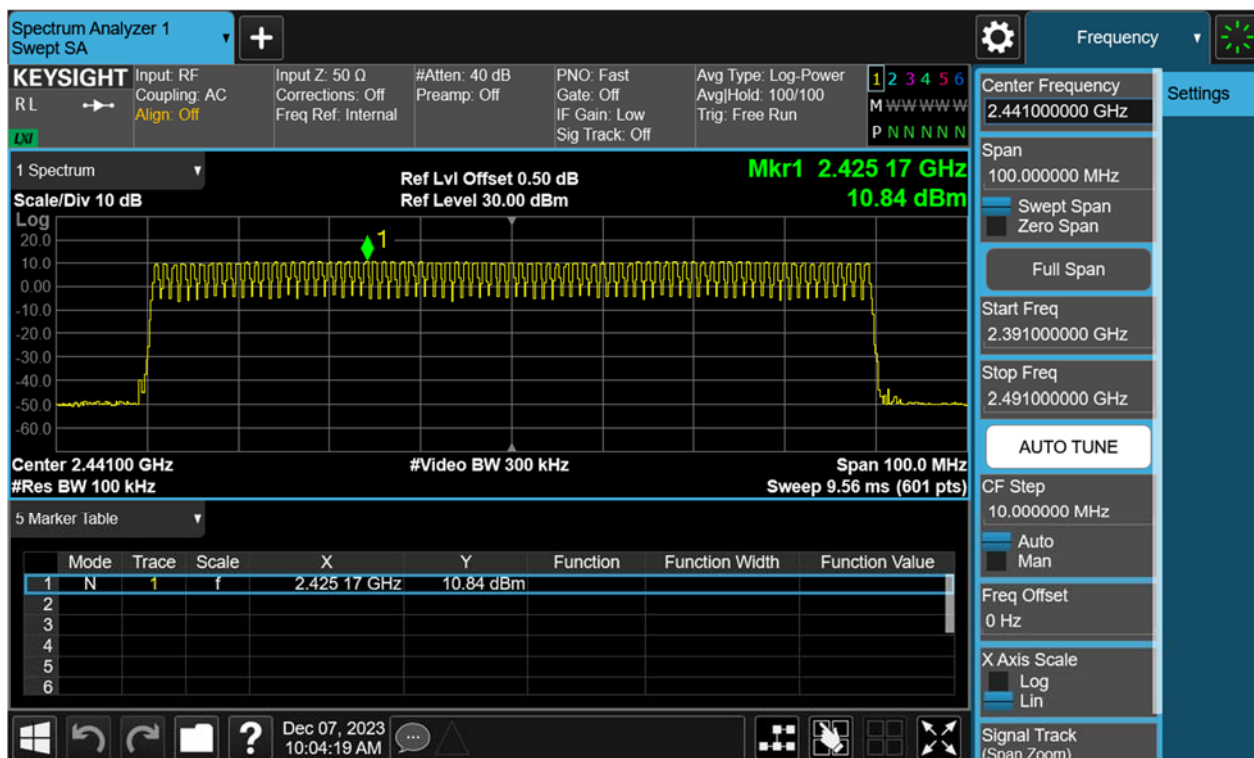


Figure 28: Conducted Spurious Emission & Authorized-band band-edge, Hopping Mode, GFSK Carrier Level



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Band Edge(Low)



Band Edge(High)



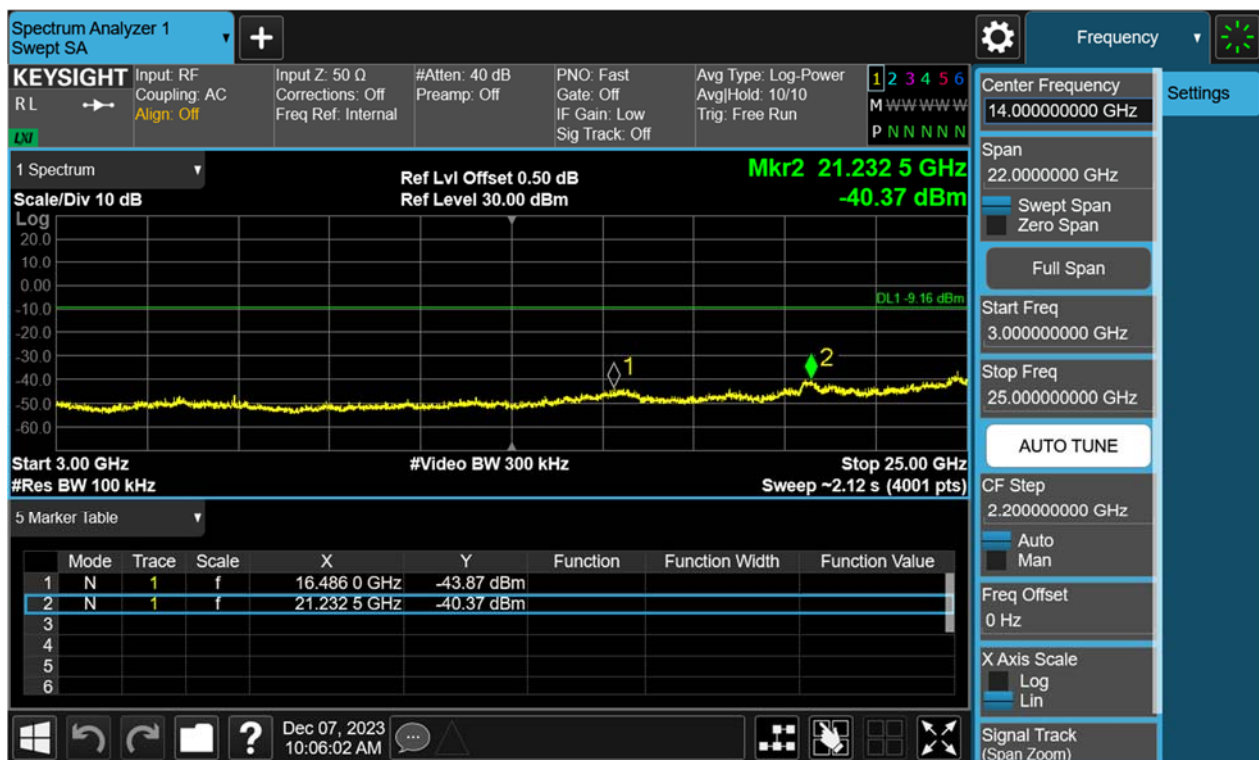
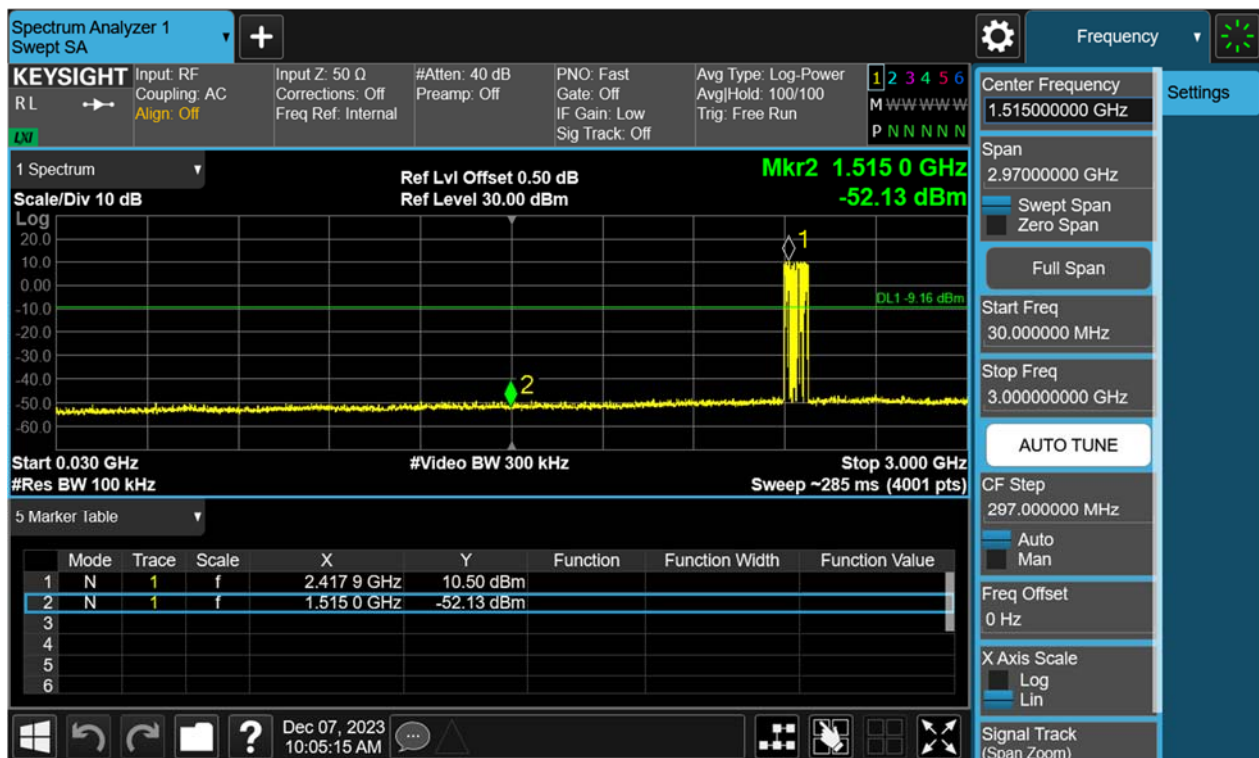
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Conducted spurious emissions 30MHz-25GHz



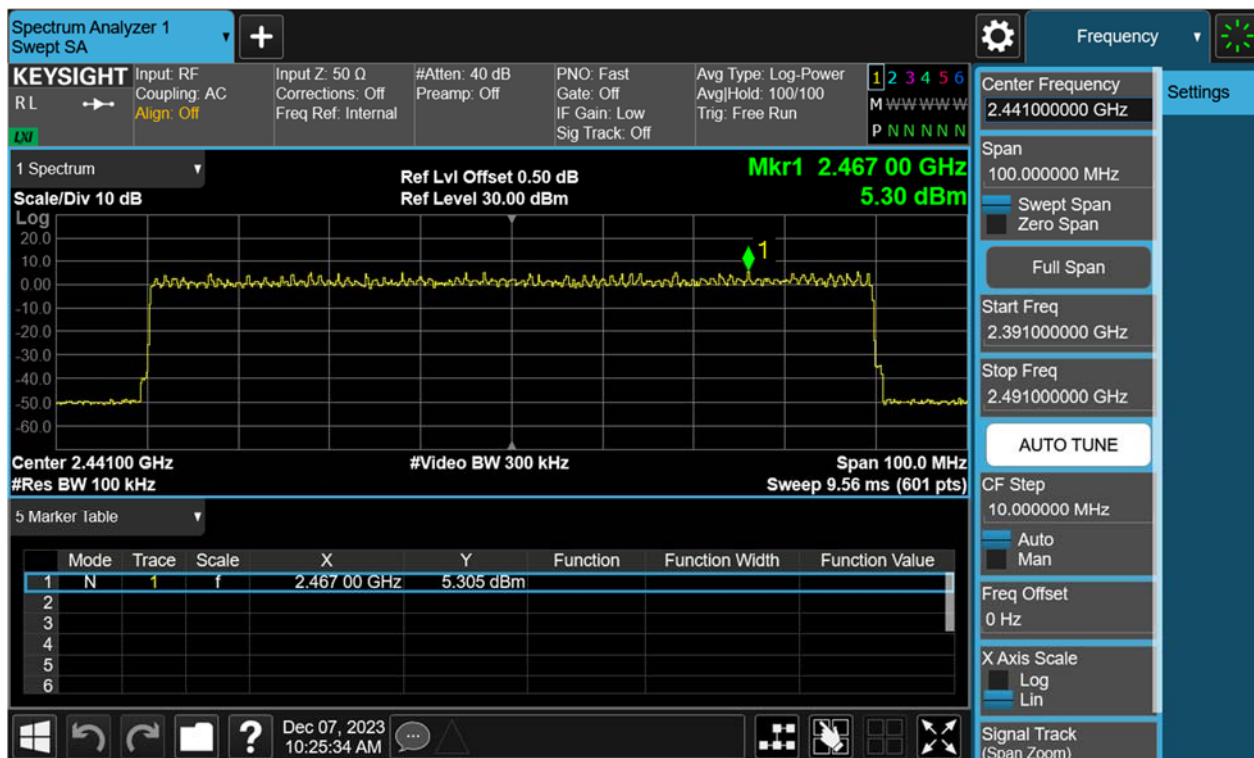
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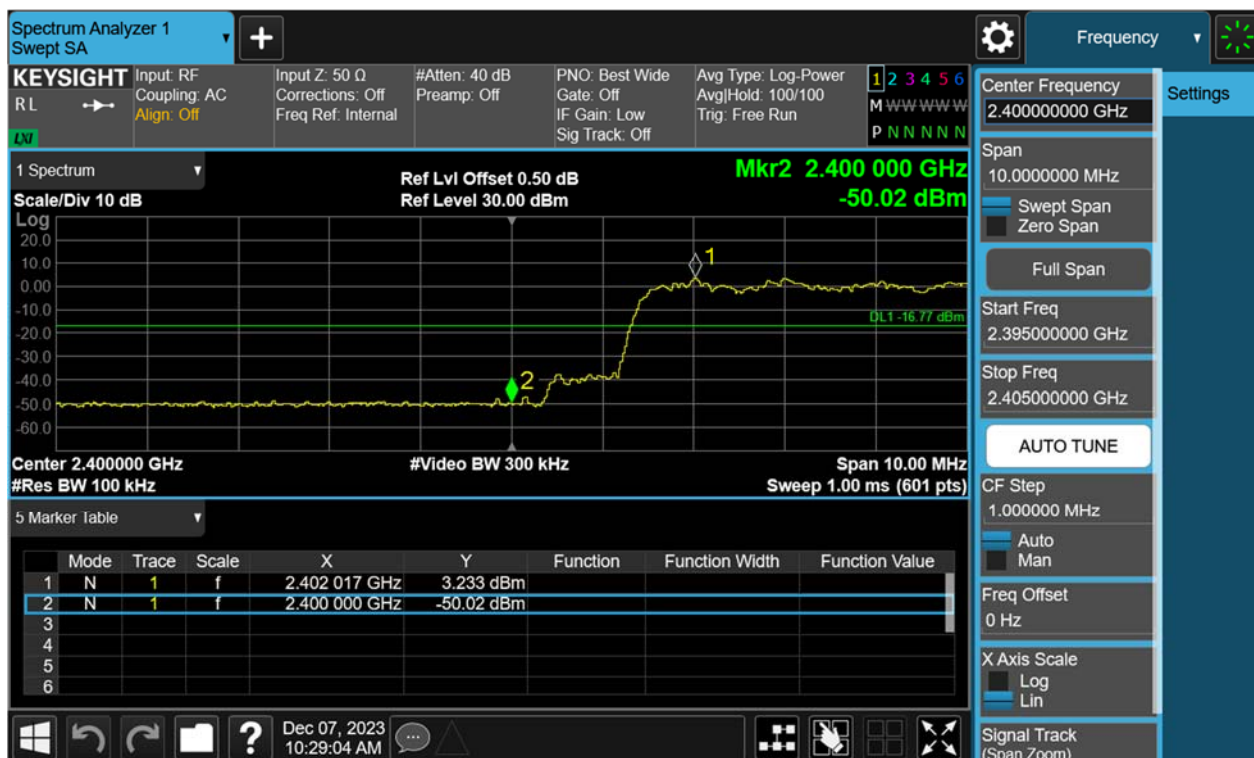
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Figure 29: Conducted Spurious Emission & Authorized-band band-edge, Hopping Mode, $\pi/4$ -DQPSK Carrier Level



Band Edge(Low)



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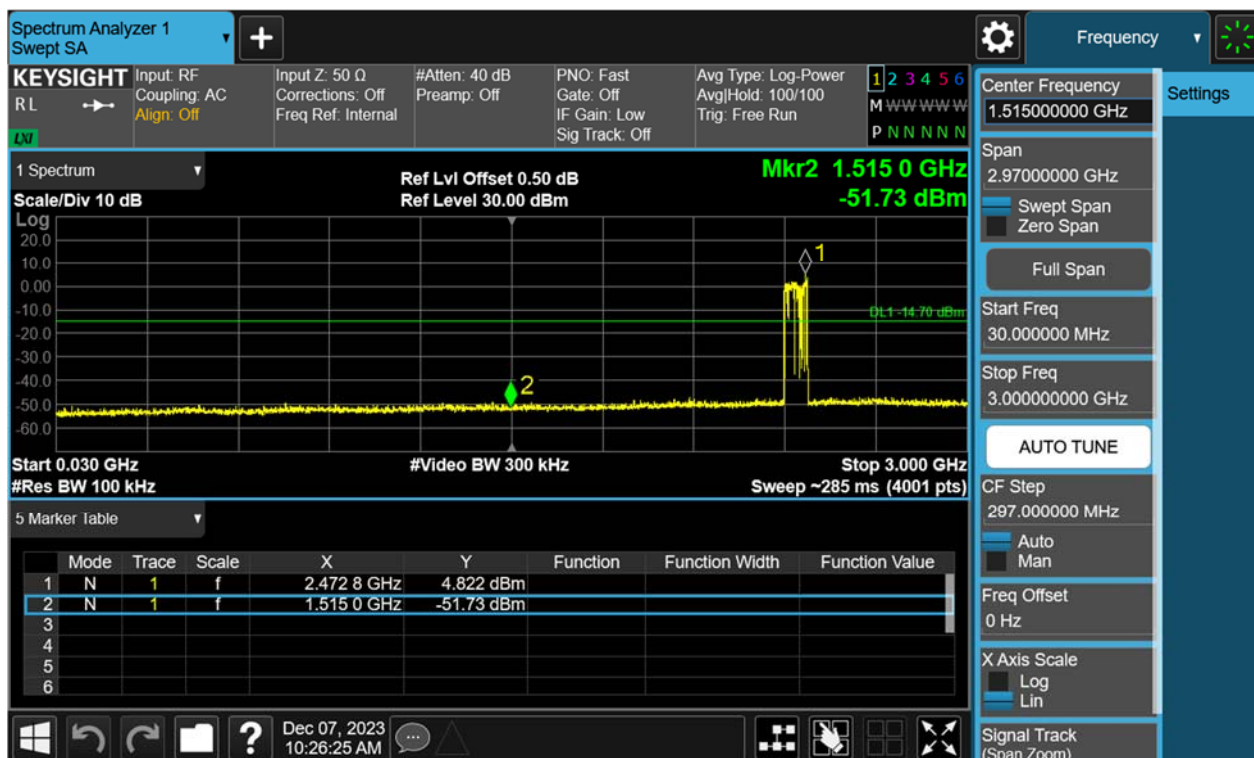
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Band Edge(High)



Conducted spurious emissions 30MHz-25GHz



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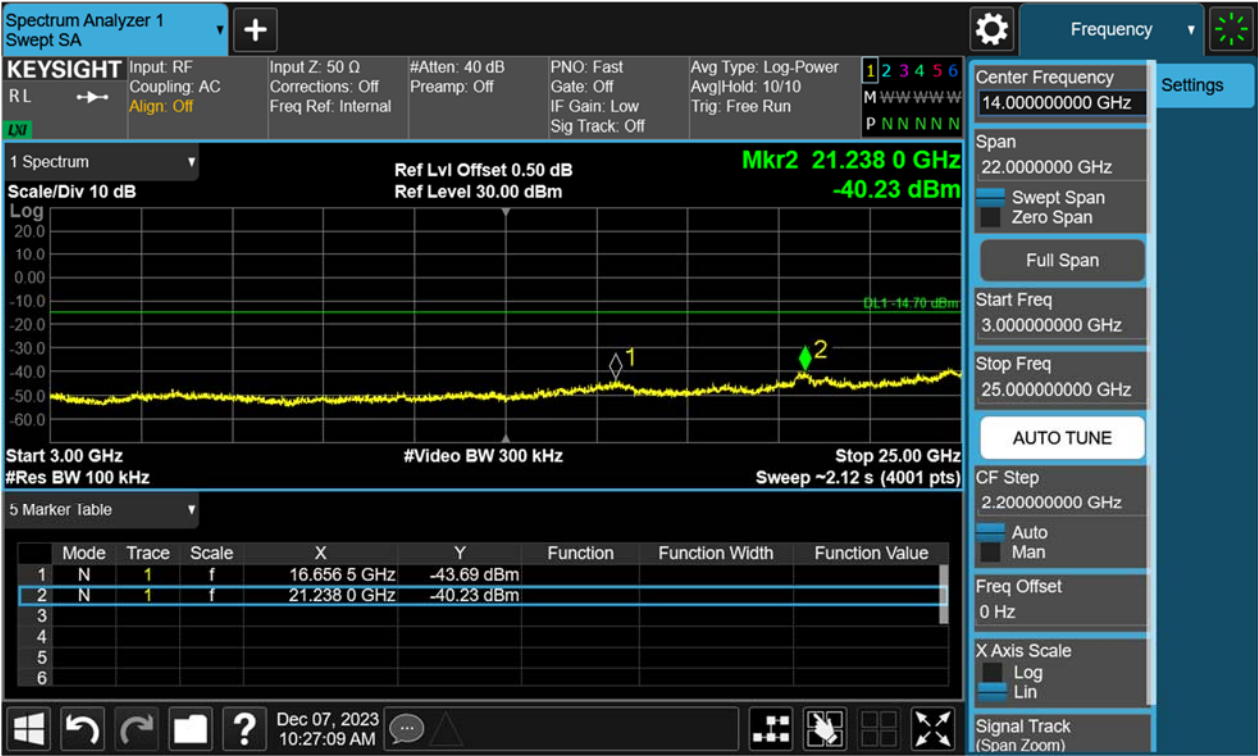
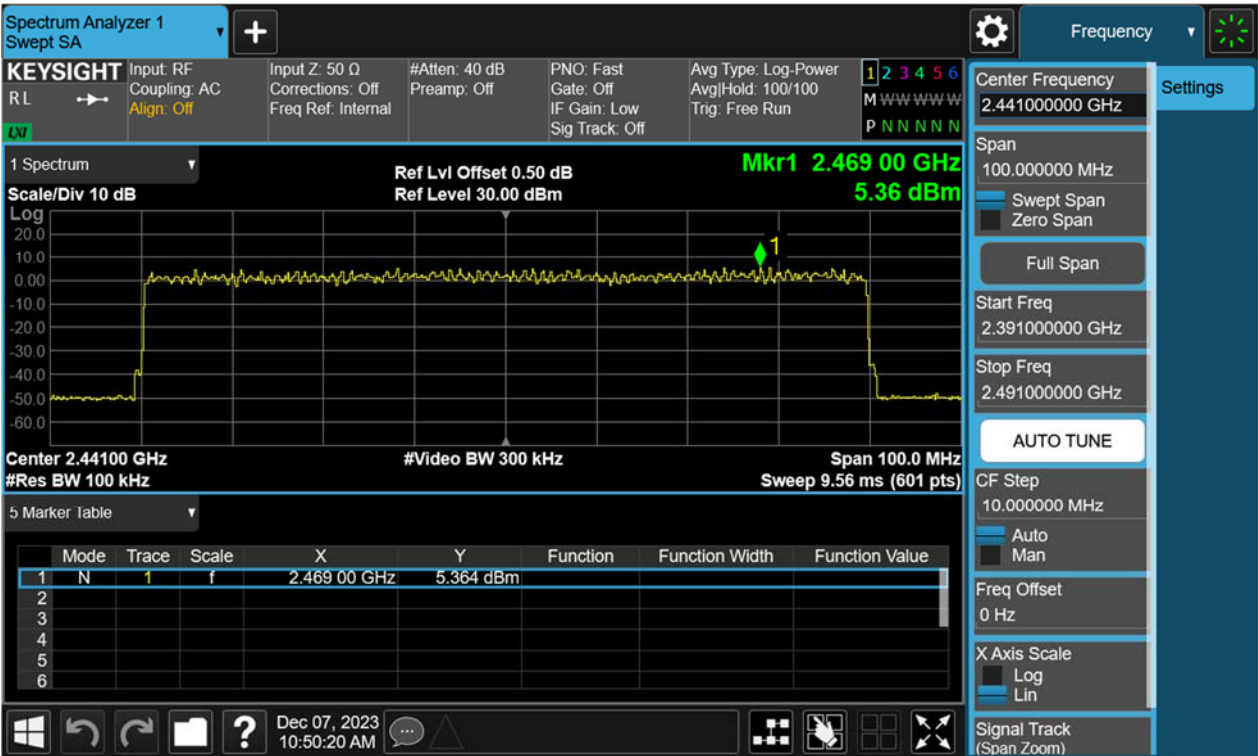


Figure 30: Conducted Spurious Emission & Authorized-band band-edge, Hopping Mode, 8-DPSK Carrier Level



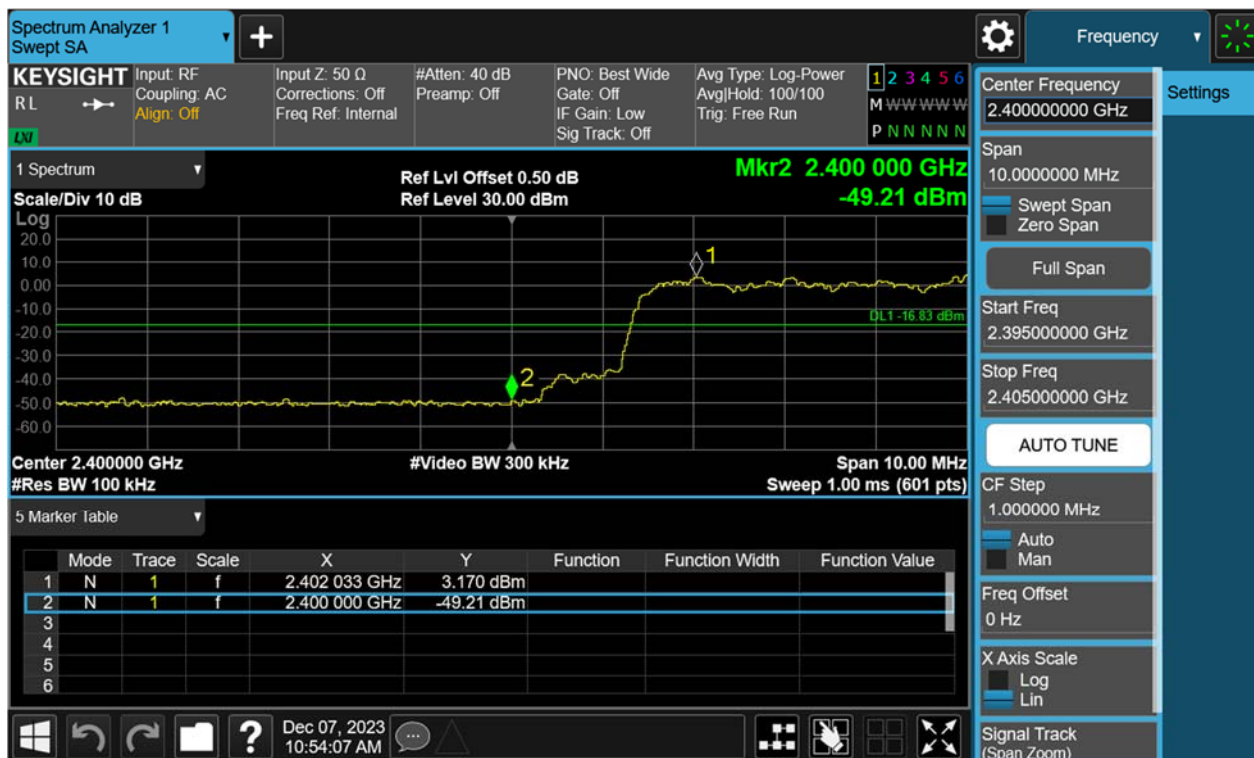
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Band Edge(Low)



Band Edge(High)



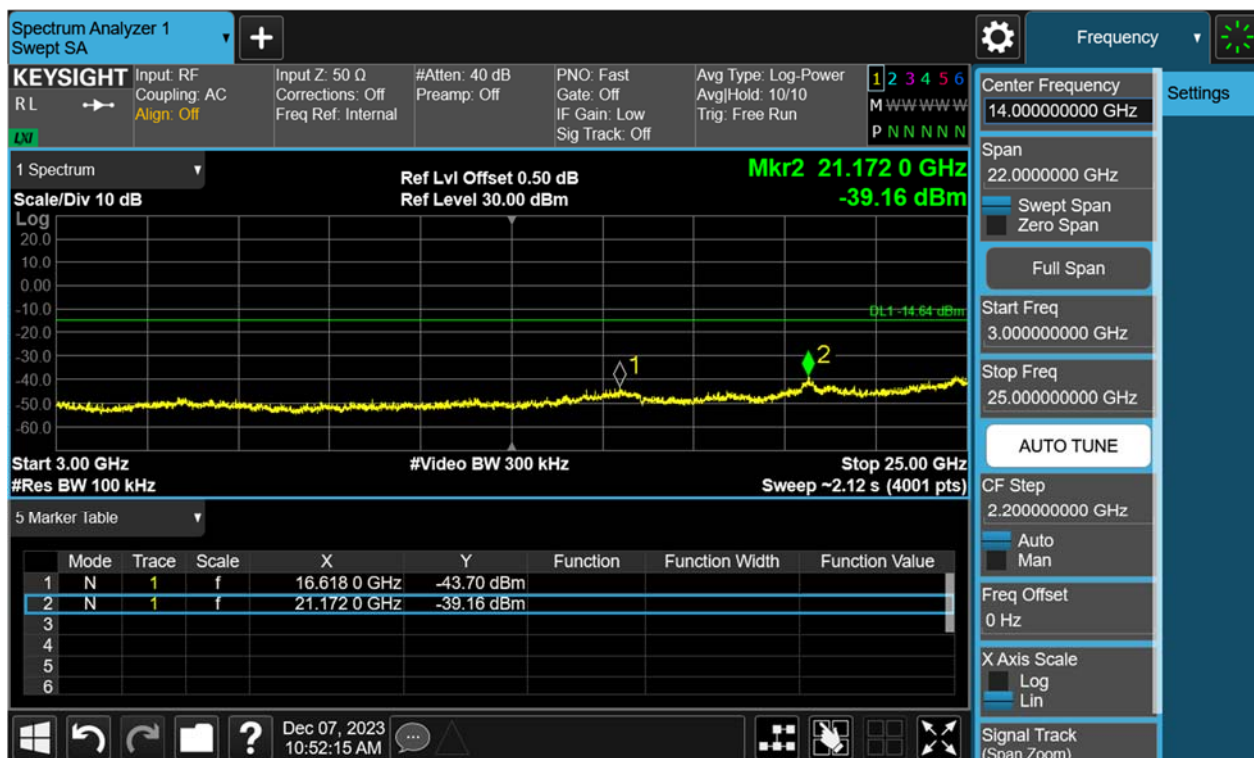
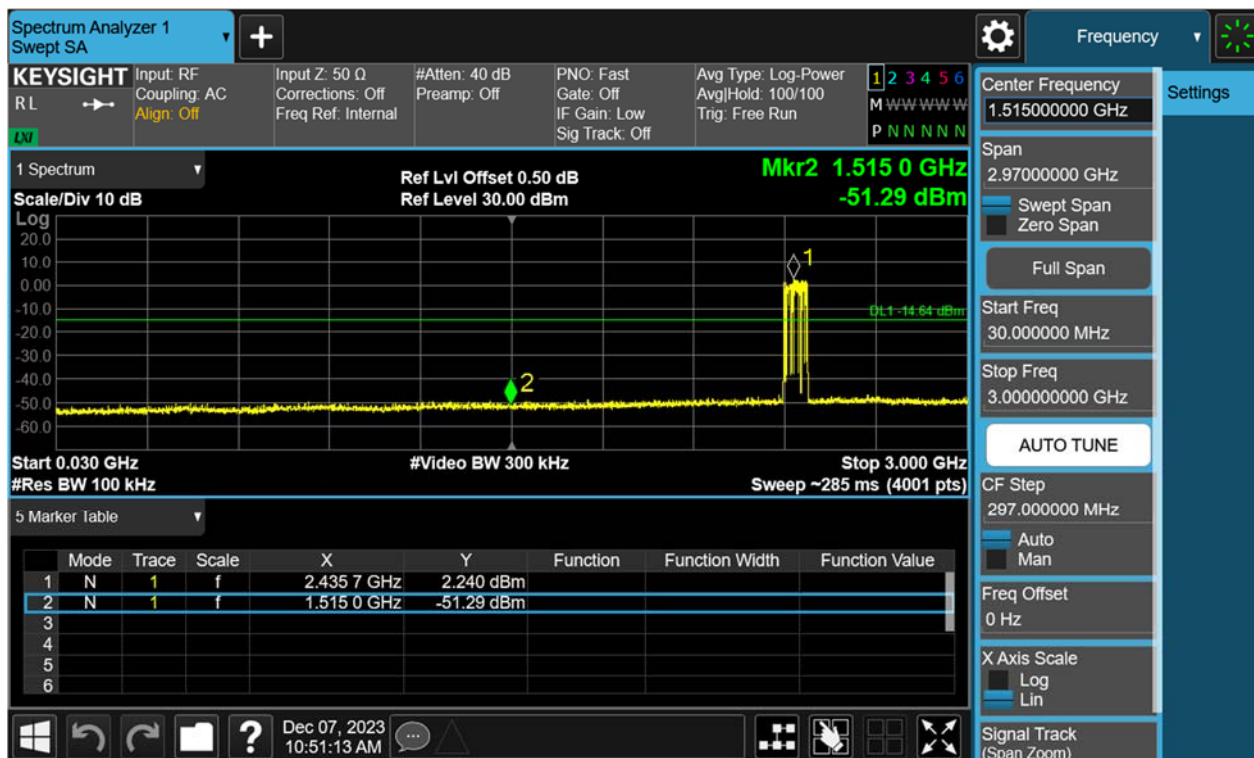
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Conducted spurious emissions 30MHz-25GHz



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4.1.5 Radiated Spurious Emission

RESULT:

PASS

Test standard	: FCC Part 15.247(d), 15.205, 15.209 RSS-GEN 8.9
Requirement	: ANSI C63.10-2013, Clause 7.8.8
Kind of test site	: 3m Semi-Anechoic Chamber

Test setup

Test Channel	: Low/Middle/High
Operation Mode	: A
Ambient temperature	: 23.5°C
Relative humidity	: 54%

Notes

Test plots please refer to the annex document "SHE23060106-02CE DATA BDEDR-TX EXHIBIT A".

- 1. For 9 kHz ~ 30 MHz, the amplitude of spurious emissions that are attenuated by more than 20dB below the permissible. The value has no need to be reported.*
- 2. The spurious above 18GHz is noise only and 20dB below the limit. The value has no need to be reported.*
- 3. All test mode had been pre-test. Only the worst mode data of GFSK&8DPSK-hopping-DH5 and GFSK&8DPSK_Middle channel (below 1GHz) were recorded in the test report.*
- 4. The EUT was pretested with 3 orientations placed on the table for the radiated emission measurement –X, Y, and Z-plane. The X-plane results were found as the worst case and were shown in this report.*

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4.1.6 Band Edge (Restricted-band band-edge)

RESULT:

PASS

Test standard	: FCC Part 15.247(d), 15.205, 15.209 RSS-GEN 8.10
Requirement	: ANSI C63.10-2013, Clause 7.8.6
Kind of test site	: 3m Semi-Anechoic Chamber

Test setup

Test Channel	: Low/Middle/High
Operation Mode	: A.1
Ambient temperature	: 23.5°C
Relative humidity	: 54%

Notes

1. Test plots please refer to the annex document "SHE23060106-02CE DATA BDED-R-TX EXHIBIT A".
2. The EUT was pretested with 3 orientations placed on the table for the radiated emission measurement –X, Y, and Z-plane. The X-plane results were found as the worst case and were shown in this report.